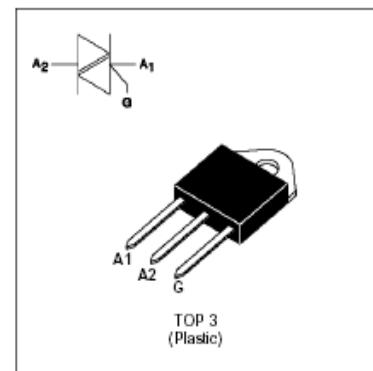


**BTA25,BTA26(25A TRIACS)**

Symbol	Value	Unit
I <sub>T(RMS)</sub>	25	A
V <sub>DRM/V<sub>RRM</sub></sub>	600 and 800	V
I <sub>G(Q1)</sub>	35 to 50	mA

**ABSOLUTE RATING**

Symbol	Parameter			Value	Units
I <sub>T(RMS)</sub>	RMS on-state current(full sine wave).		T <sub>C</sub> =90°C	25	A
	Non-repetitive peak on-state current(T <sub>j</sub> =25°C, full cycle)	F=50Hz	t=20ms	250	
		F=60Hz	t=16.7ms	260	
dI/dt	Critical rate of rise of on-state current I <sub>G</sub> =2×IGT, t <sub>r</sub> ≤100ns	F=120Hz	T <sub>j</sub> =125°C	50	A/μ s
I <sub>GM</sub>	Peak gate current	t <sub>p</sub> =20 μ s	T <sub>j</sub> =125°C	4	A
P <sub>G(AV)</sub>	Average gate power dissipation		T <sub>j</sub> =125°C	1	W
T <sub>stg</sub>	Storage junction temperature range			-40~150	°C
T <sub>j</sub>	Operating junction temperature range			-40~150	°C

**THERMAL RESISTANCE**

Symbol	Parameter	Value	Unit
R <sub>th(j-c)</sub>	Junction to case	1.1	°C/W
R <sub>ti(j-a)</sub>	Junction to ambient	50	°C/W

## ELECTRICAL CHARACTERISTICS ( $T_j=25^\circ\text{C}$ unless otherwise stated)

Symbol	Testing conditions	Quadrant		Suffix			Unit
				CW	BW	B	
$I_{GT}$	$V_D=12\text{V}$ , $R_L=33\ \Omega$	I - II - III	Max	35	50	50	mA
		IV		-	-	100	
$V_{GT}$		ALL	Max	1.3			V
$V_{GD}$	$V_D=V_{DRM}$ , $R_L=3.3\text{K}\ \Omega$ , $T_j=125^\circ\text{C}$	ALL	Min	0.2			V
$I_L$	$I_G=1.2I_{GT}$	I - III	Max	70	80	70	mA
		II		80	100	160	
$I_H$	$I_T=500\text{mA}$	ALL	Max	35	50	50	mA
$V_{TM}$	$I_T=35\text{A}$ , $t=380\ \mu\text{s}$	ALL	Max	1.55			V
$I_{DRM}$ $I_{RRM}$	$V_{DRM}=V_{RRM}$	$T_j=25^\circ\text{C}$	Max	5			$\mu\text{A}$
		$T_j=125^\circ\text{C}$		3			mA
$dv/dt$	$V_D=67\% V_{DRM}$ Gate open $T_j=125^\circ\text{C}$		Min	500	1000	500	V/ $\mu\text{s}$